

Search Notes

Application/Control No.

10/674,355

Examiner

Chase Peers

Applicant(s)/Patent under
Reexamination

CHEN, CHIH-WEI

Art Unit

2186

SEARCHED

Class	Subclass	Date	Examiner
711	1,103	10/4/2005	CP
711	170	10/4/2005	CP
713	2	10/4/2005	CP
717	168,170	10/4/2005	CP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched the East databases for like terms and limited to 711/103	10/4/2005	CP
Searched NPL for like terms	10/4/2005	CP